- Flow-Through Architecture Optimizes **PCB** Layout
- Center-Pin V<sub>CC</sub> and GND Configuration **Minimizes High-Speed Switching Noise**
- EPIC<sup>™</sup> (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip **Carriers, and Standard Plastic and Ceramic** 300-mil DIPs

#### description

These devices contain four independent 2-input NOR gates. They perform the Boolean functions  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic.

The 54AC11002 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11002 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each gate) INPUTS OUTPUT

Α	В	Y
н	Х	L
Х	Н	L
L	L	Н

### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

EPIC is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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54AC11002 J PACKAGE 74AC11002 D OR N PACKAGE (TOP VIEW)								
1A [ 1Y [ 2Y [ GND [ GND [ 3Y [ 4B [	1 2 3 4 5 6 7 8	16 15 14 13 12 11 10 9	1B 2A 2B V <sub>CC</sub> V <sub>CC</sub> 3A 3B 4A					

54AC11002 ... FK PACKAGE (TOP VIEW)



NC - No internal connection

## logic diagram (positive logic)



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	
Output voltage range, V <sub>O</sub> (see Note 1)	$-0.5$ V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub> )	±20 mA
Output clamp current, $I_{OK}$ (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

#### recommended operating conditions

			54	AC1100	2	74	AC1100	2	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	3	5	5.5	V
		V <sub>CC</sub> = 3 V	2.1			2.1			
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V
		V <sub>CC</sub> = 5.5 V	3.85			3.85			
		$V_{CC} = 3 V$			0.9			0.9	
VIL	Low-level input voltage	$V_{CC} = 4.5 V$			1.35			1.35	V
		V <sub>CC</sub> = 5.5 V			1.65			1.65	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 3 V$			-4			-4	
ЮН	High-level output current	$V_{CC} = 4.5 V$			-24			-24	mA
		V <sub>CC</sub> = 5.5 V			-24			-24	
		V <sub>CC</sub> = 3 V			12			12	
IOL	Low-level output current	V <sub>CC</sub> = 4.5 V			24			24	mA
		V <sub>CC</sub> = 5.5 V			24			24	
$\Delta t / \Delta v$	Input transition rise or fall rate		0		10	0		10	ns/V
T <sub>A</sub>	Operating free-air temperature		-55		125	-40		85	°C



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	TEST CONDITIONS	м	T <sub>A</sub> = 25°C			54AC1	1002	74AC11002		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		2.9		
	I <sub>OH</sub> = - 50 μA	4.5 V	4.4			4.4		4.4		
Vон		5.5 V	5.4			5.4		5.4		
	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		V
		4.5 V	3.94			3.7		3.8		v
	I <sub>OH</sub> = – 24 mA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
		3 V			0.1		0.1		0.1	
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
Ve	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	V
VOL	1 - 24 = 24	4.5 V			0.36		0.5		0.44	V
	I <sub>OL</sub> = 24 mA	5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
Ц	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μA
ICC	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V			4		80		40	μA
Ci	$V_I = V_{CC}$ or GND	5 V		3.5						pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

## switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T <sub>A</sub> = 25°C		54AC11002		74AC11002		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
<sup>t</sup> PLH	A or B	V	1.5	7	8.6	1.5	10.7	1.5	9.9	
<sup>t</sup> PHL	AUIB	T	1.5	6	7.5	1.5	9	1.5	8.4	ns

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T <sub>A</sub> = 25°C			54AC11002		74AC11002		UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	A or B	V	1.5	4.5	6.1	1.5	7.4	1.5	6.9	ns
<sup>t</sup> PHL	AUB	I	1.5	4	5.7	1.5	6.8	1.5	6.4	115

## operating characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per gate	$C_L = 50 \text{ pF}, \text{ f} = 1 \text{ MHz}$	32	pF



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#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A.  $C_{\mbox{L}}$  includes probe and jig capacitance.
  - B. Input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub> = 3 ns, t<sub>f</sub> = 3 ns.
  - C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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